H. Display and Imaging Technologies 분과

2020년 2월 13일(목), 10:45-12:30 / Room C (사파이어 I, 5층)

▌[TC2-H] Image Engineering & Sensors

좌장: 권혁인 교수 (중앙대학교),오누리 교수 (한양대학교)

TC2-H-1 10:45-11:15	**[초청]** **Recent Technology Trends in Mobile Imaging Applications** Jae-kyu Lee, Min-Woong Seo, Tae-Yon Lee, Myunglae Chu, Hyunchul Kim, JungChak Ahn, and Ho-kyu Kang *Semiconductor R&D Center, Samsung Electronics Co., Ltd.*
TC2-H-2 11:15-11:30	**A Methodology for In-Fab Evaluation of Pinned Photodiode in CMOS Image Sensors** Dongseok Cho, Sungin Kim, Jonghyun Go, Hyunchul Kim, Jaekyu Lee, and Jungchak Ahn *Semiconductor R&D Center, Samsung Electronics Co., Ltd.*
TC2-H-3 11:30-11:45	**High-Sensitive And Transparent Strain Sensor Using Strain Engineered Substrate and Its Application For Human Motion Detection** Inki Hwang, Daesik Kim, Geonhee Kim, and Yongtaek Hong *Department of Electrical and Computer Engineering and Inter-University Semiconductor Research Center (ISRC), Seoul National University*
TC2-H-4 11:45-12:00	**Advanced Optical Collimator for Large Area OLED Fingerprint Sensor** Ji Hun Ryu, Seung Hyun Moon, Chul Kim, Won Sang Park, and Bong-Hyun You *Samsung Display Co., Ltd*
TC2-H-5 12:00-12:15	**2 Dimensional van der Waals Heterojunction Diode for Multiband Photo Detection** Jongtae Ahn[1,2], Hyun-soo Ra[1], and Do Kyung Hwang[1] *[1]Center for Opto-electronic Materials and Devices, Post-silicon Semiconductor Institute, KIST, [2]Yonsei University*
TC2-H-6 12:15-12:30	**Pressure-Sensitive Thin-Film Transistors Using Capacitance Modulation via Multiscale Surface Morphology of Embedded AgNWs** Hayun Kim, Byeongmoon Lee, Hyunuk Oh, Hyunjun Yoo, Jaeyoung Yoon, and Yongtaek Hong *Department of Electrical and Computer Engineering and Inter-University Semiconductor Research Center (ISRC), Seoul National University*